

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/501,687	VAN DER VLEUTEN ET AL.	
	Examiner	Art Unit	Page 1 of 1
	Seokyun Moon	2675	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,523,769	06-1996	Lauer et al.	345/1.3
*	B	US-5,565,885	10-1996	Tamanoi, Yutaka	345/100
*	C	US-5,576,738	11-1996	Anwyl et al.	345/212
*	D	US-6,529,181	03-2003	Nakano et al.	345/98
*	E	US-4,903,013	02-1990	Takeda, Susumu	345/686
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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